



Contacts:

Aehr Test Systems

Greg Perkins

V.P. Worldwide Sales & Service

(510) 623-9400 x241

Financial Relations Board

Erin Cox

Analyst/Investor Contact

(310) 854-8319

**AEHR TEST SYSTEMS RECEIVES FOLLOW-ON FOX™ ORDERS
FROM A MAJOR IC MANUFACTURER**

Fremont, CA (March 27, 2007) - Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received repeat orders from a leading memory IC manufacturer totaling over \$8 million for its FOX-1 full wafer parallel test systems and full wafer contactors. The systems and contactors are scheduled to ship during the next six months.

"It is important to recognize that this is yet another significant large volume of FOX-1 orders from this customer," said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. "The customer has ordered FOX-1 systems for multiple production locations, which we believe demonstrates the customer's confidence in Aehr Test's full wafer technology, as well as our clear market leadership in this segment."

The FOX-1 full wafer parallel test system, a member of the FOX family of full wafer contact systems, is designed to test an entire wafer of IC devices in a single touchdown or to be utilized for short burn-in and test applications. This innovative solution combines full wafer contact, massively parallel test and Design For Test (DFT) technologies. Other members of Aehr Test's FOX family of products such as the FOX-14 and FOX-V, are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX and MAX systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technology, acceptance by customers of the FOX systems and contactors shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

###